

08/C917
118 715
Class Subclass
ISSUE CLASSIFICATION

UTILITY SERIAL NUMBER 08/691434	PATENT DATE	PATENT NUMBER 2822
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SERIAL NUMBER 08/691.434	FILING DATE 08/02/96	CLASS 1-17	SUBCLASS	GROUP ART UNIT 2822	EXAMINER WLUK
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SHUNPEI YAMAZAKI, TOKYO, JAPAN; AKIRA TAKENOUCHI, KANAGAWA, JAPAN;
YASUHIRO TAKEMURA, KANAGAWA, JAPAN. 2822

CONTINUING DATA***
VERIFIED: THIS APPLN IS A CON OF 08/160,909 12/03/93 ABN
Mw

FOREIGN/PCT APPLICATIONS***
VERIFIED: JAPAN 4-350546 12/04/92
JAPAN 5-301172 11/05/93
Mw

ABANDONED



Foreign priority claimed 35 USC 119 conditions met	<input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> yes <input type="checkbox"/> no	AS FILED	STATE OR COUNTRY JPX	SHEETS DRWGS. 5	TOTAL CLAIMS 67	INDEP. CLAIMS 11	FILING FEE RECEIVED \$2,658.00	ATTORNEY DOCKET # 0756-
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SIXBEY FRIEDMAN LEEDOM & FERGUSON
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MCLEAN VA 22102

METHOD OF FABRICATING SEMICONDUCTOR DEVICES AND APPARATUS FOR
PROCESSING A SEMICONDUCTOR

U.S. DEPT. OF COMM./PAT. & TM-PTO

PARTS OF A FILED/SEPA
NOTICE OF
Amount Due \$1210

DRAWINGS			CLAIMS ALLOWED	
Sheets Drwg. 5	Figs. Drwg. 11	Print Fig. 2	Total Claims 24	Print Claim for O.G. 1
(Assistant Examiner) (Date) M. Wilczewski 10/04 MARY WILCZEWSKI PRIMARY EXAMINER M. Wilczewski 1/03 (Primary Examiner) (Date) A. O. Webb (Legal Instruments Examiner) (Date)			NOTICE OF ALLOWANCE MAILED 11/3/04 1/28/05 ISSUE FEE \$0 Amount Due \$1,370 Date Paid ISSUE BATCH NUMBER	

Form PTO-436A
(Rev. 8/92)

QUER 783-36

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